



IPW

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of )

Yehiel Gotkis )

Application No. 10/810,209 )

Filed: March 26, 2004 )

For: METHOD AND APPARATUS FOR )  
MEASUREMENT OF THIN FILMS AND )  
RESIDUES ON SEMICONDUCTOR )  
SYBSTRATES )

) Examiner: Unassigned

) Art Unit: 1765

) Docket No. LAM2P466

) Date: March 28, 2005

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on March 28, 2005.

Signed: \_\_\_\_\_

Kay Harlow

**REQUEST TO RESCIND PREVIOUS NONPUBLICATION REQUEST &  
NOTICE OF FOREIGN FILING**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

A request that the above-identified application not be published under 35 U.S.C. 122(b) (non-publication request) was included with the above-identified application on filing pursuant to 35 U.S.C. 122(b)(2)(B)(i).

I hereby **RESCIND** the previous non-publication request. If a **notice** of foreign or international filing is or will be required by 35 U.S.C. 122(b)(2)(B)(iii) and 37 CFR 1.213(c), I hereby provide such **NOTICE**. This notice is being provided no later than forty-five (45) days after the date of such foreign or international filing.

Respectfully submitted,  
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